We present the results of single event effects (SEE) testing and analysis investigating the effects of radiation on electronics. This paper is a summary of test results.

### Test Techniques and Setup

**A. Test Indications**
- Single event functional interrupts (SEFI)
- Pixel artifacts
- Catastrophic failures

**B. Test Setup**
- Single event effects (SEE)
- Ground-based testing
- Candidate spacecraft electronics
- Single event burnout (SEB)
- Single event transient (SET)
- Radiation environment

**C. Test Facilities**
- University Cyclotron Facility
- University Cyclotron Facility
- University Cyclotron Facility
- University Cyclotron Facility
- University Cyclotron Facility

**D. Test Conditions**
- Flux: 1x10^7 to 1x10^9 p+/cm^2-
- Particles/cm^2
- Let: 1.84

**E. Test Duration**
- 24kHz output frequency
- No more than 100x lens

### Test Results Overview

**Table V: Summary of SEE Test Results**

<table>
<thead>
<tr>
<th>Device</th>
<th>Die Size</th>
<th>Voltage</th>
<th>Current</th>
<th>Capacity</th>
<th>Efect</th>
<th>LET (T)</th>
<th>LET (R)</th>
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### References

[20] University Cyclotron Facility. As of the publication of this paper, the facilities are commercially available.

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